

# Search Notes



Application/Control No.

10/784,326

Examiner

Kin-Chan Chen

Applicant(s)/Patent under Reexamination

LEE ET AL.

Art Unit

1765

## SEARCHED

Class	Subclass	Date	Examiner
438	700	11/23/2005	KCC
	706		
	719		
	720		
	723		
438	724		
	221		
	296		
438	427	11/23/05	KCC

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East Keyword search USPT, uspg-pub. Epo, Jpo, Perwent TBM-708, inventor search	11/18/2005	KCC